

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	548	117/2.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 08:51
L2	468	117/3.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 09:13
L3	260	117/14.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 10:02
L5	1197	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:14
L6	60	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (bmd or oxygen near2 precipitat\$3 or bulk adj microdefect or bulk adj micro adj defect)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:33

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L7	62	("20010032581" "20020170631" "20020179006" "20030022003" "20030051656" "20030068890" "4314595" "4376657" "4437922" "4505759" "4548654" "4851358" "4868133" "5024723" "5189500" "5194395" "5327007" "5374564" "5401669" "5403406" "5436175" "5445975" "5478408" "5502010" "5502331" "5508207" "5534294" "5539245" "5593494" "5611855" "5674756" "5738942" "5788763" "5882987" "5939770" "5944889" "5954873" "5994761" "6180220" "6190631" "6191010" "6204152" "6221743" "6236104" "6245645" "6284384" "6306733" "6336968" "6339016" "6361619" "6432197" "6485807" "6503594" "6537368" "6537655" "6544656" "6579779" "6586068" "6666915" "6669777" "6673147" "6897084").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/13 10:57
L8	1	"20050253221"	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/13 10:57
L9	2	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (seco or secco) near2 (etching)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:31
L10	13	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (bmd or oxygen near2 precipitat\$3 or bulk adj microdefect or bulk adj micro adj defect) near5 (size or radius or diameter or microns or micrometers or nm or nanometers)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:23
L12	21	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (oxygen) near4 (density or concentration) and (carbon) near4 (density or concentration)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:28

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L13	2	"20030068890"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:28
L14	18	(rf or radio adj frequency or high adj frequency or microwave) near4 (silicon or si) near (substrate or wafer) and (bmd or oxygen near2 precipitat\$3 or bulk adj microdefect or bulk adj micro adj defect)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:11
L15	25	(rf or radio adj frequency or high adj frequency or microwave) near4 (silicon or si) near (substrate or wafer) and carbon near2 (concentration or density)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:31
L16	8	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (seco or secco)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:43
S2	7	"6858094".pn. "20040005777".pn. "6544656".pn. "5502331".pn.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 08:35
S3	4100	438/17.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 16:18
S4	198	438/17.ccls. and (silicon or wafer) near6 (resistivity or resistance or (defect or dislocation or bmd or precipitate) near2 (density or concentration))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 16:23

EAST Search History

S5	157	438/143.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:02
S6	.80	438/402.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:25
S7	493	438/471.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:33
S8	251	438/799.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:46
S9	158	257/610.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:57
S10	148	257/611.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 18:04
S11	136	257/612.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 18:06

EAST Search History

S12	526	257/655.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 18:06
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